

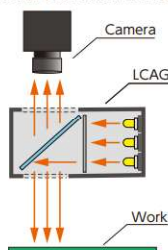
Coaxial Epi-Illumination «LCAG Series»

LCAG Series

Irradiates diffused light in the same axial direction as camera.



Irradiates diffused light in the same axial direction as camera axis through a half mirror.



Customizable



Features

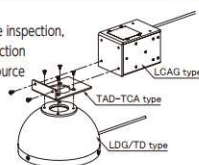
- Irradiation in the same axial direction as camera through a half mirror.
- Clarifies contrast in detection targets (dents, scratches, engraved marks, etc.).
- Enables uniform irradiation on mirror surfaces.
- Best suited for inspection of reflective metals, films, and plastics.
- Wide range of applications such as electronic parts, printing, food processing, and medical treatment.

Visual inspection of lead frames



Application example

Measurement of dimensions, printed circuit board trace inspection, scratches/engraved mark/dent inspection, shape inspection
Area camera light source and image processing light source

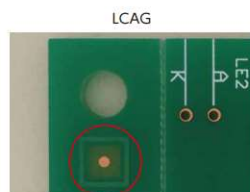


Example of imaging

- Alignment of mounted boards



Difficult to detect an alignment mark due to reflection of light onto the board surface



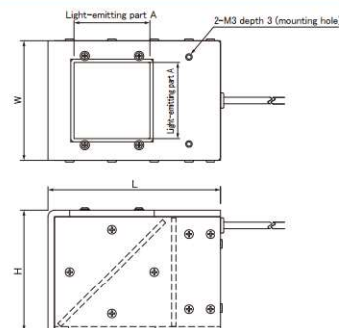
An alignment mark on a glossy surface can be stably detected.

Product Specifications

Model	LxWxH [mm]	Light-emitting part A [mm]	Maximum rated current [A]	Power consumption [W]	Input voltage [V]	Example of applicable power supply
LCAG25NW-E41	65x40x41	20	0.13	3.1	24	TPDP1B-2410NCW
LCAG40NW-E41	80x55x56	35	0.25	5.9	24	TPDP1B-2410NCW
LCAG55NW-E41	95x70x71	50	0.36	8.6	24	TPDP1B-2430NCW
LCAG80NW-E41	125x95x96	75	0.46	11.1	24	TPDP1B-2430NCW
LCAG105NW-E41	150x120x121	100	0.55	13.3	24	TPDP1B-2430NCW

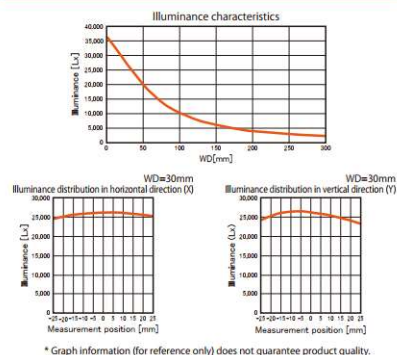
● For details about other sizes, contact our sales department.

Outer dimensions



* Product specifications are subject to change without notice.

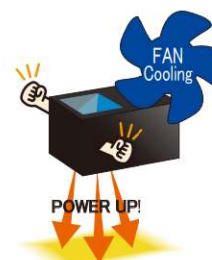
Data (Typical example : LCAG105NW-E41)



* Graph information (for reference only) does not guarantee product quality.

Example of customization

Efficient cooling design allows for high-power illumination.



- High-speed for production lines
- Clarifies contrast by maintaining a distance from the work.

High power facilitates longer sample distance for more accurate defect detection.